

Find PDF

ELECTRICAL CHARACTERIZATION OF SiC USING DLTS SYSTEM



VDM Verlag Dr. Mäüller. Paperback. Book Condition: New. Paperback. 72 pages. Dimensions: 8.7in. x 5.9in. x 0.2in. Experiments were carried out on a high blocking voltage Schottky diode (2KV) fabricated on an n-type 4H-polytype Silicon Carbide. The sample is low doped in low 10^{14} (carrier concentration is $2.4 \times 10^{14} \text{ cm}^{-3}$) and thickness of epitaxial layer is 30um. The substrate is n-type of doping in the mid 10^{18} range. Silicon carbide (SiC) is selected because it has a wide bandgap, high...

Read PDF Electrical Characterization of SiC using DLTS System

- Authored by Muhammad Rizwan Qayyum
- Released at -



Filesize: 5.44 MB

Reviews

This ebook may be worth a go through, and superior to other. I could comprehend every thing out of this published e pdf. It is extremely difficult to leave it before concluding, once you begin to read the book.

-- **Prof. Damien Schuster PhD**

The ebook is fantastic and great. I really could comprehend every thing out of this published e publication. You can expect to like the way the blogger write this publication.

-- **Precious Farrell**

This publication is definitely not effortless to get started on studying but extremely enjoyable to see. I was able to comprehend almost everything using this created e pdf. I am pleased to let you know that here is the finest publication i have go through in my very own lifestyle and could be the very best pdf for ever.

-- **Prof. Juliana Langosh DVM**